

| L Number | Hits | Search Text | DB | Time stamp |
|----------|-------|---|---|------------------|
| 1 | 2 | "6713351" | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2004/07/20 12:03 |
| 2 | 2 | "6636447" | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2004/07/20 12:05 |
| 3 | 2 | "6388283" | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2004/07/20 14:47 |
| 4 | 14627 | common adj terminal | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2004/07/20 14:48 |
| 5 | 4640 | trench\$2 adj capacitor\$1 | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2004/07/20 14:48 |
| 6 | 12 | (common adj terminal) and (trench\$2 adj capacitor\$1) | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2004/07/20 14:49 |
| 7 | 3248 | (trench\$2 adj capacitor\$1) and DRAM | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2004/07/20 14:50 |
| 8 | 2558 | different adj row | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2004/07/20 14:52 |
| 9 | 5 | ((trench\$2 adj capacitor\$1) and DRAM) and (different adj row) | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2004/07/20 14:57 |
| 10 | 85230 | DRAM | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2004/07/20 14:57 |
| 11 | 213 | (common adj terminal) and DRAM | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2004/07/20 15:01 |
| 12 | 20357 | power adj converter | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2004/07/20 15:01 |

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|----|-------|---|---|------------------|
| 13 | 189 | ((common adj terminal) and DRAM) and (not (power adj converter)) | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2004/07/20 15:11 |
| 14 | 31484 | connecting adj line\$1 | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2004/07/20 15:12 |
| 15 | 33 | (trench\$2 adj capacitor\$1) and (connecting adj line\$1) | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2004/07/20 15:12 |

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| 12 | 20357 | power adj converter | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2004/07/20 15:01 |

EAST - (thinsearch15.wsp:1)

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Active

- L1: (2) "6713351"
- L2: (2) "6636447"
- L3: (2) "6388283"
- L4: (14627) common adj terminal
- L5: (4640) trench\$2 adj capacitor\$1
- L6: (12) 4 and 5
- L7: (3248) 5 and DRAM
- L8: (2558) different adj row
- L9: (5) 7 and 8
- L10: (85230) DRAM
- L11: (213) 4 and 10
- L12: (20357) power adj converter
- L13: (189) 11 and (not 12)
- L14: (31484) connecting adj line\$1
- L15: (33) 5 and 14
- L16: (3730) connecting adj region\$1
- L17: (26) 5 and 16

Failed

DB: USPAT:US PGPU:EPD:IPD:DERWENT:IBM:108

Default operator: OR

5 and 16

7/20/04 TTN

Buttons: Browse, Query, Draw

Buttons: BRS here, SAR here, Image, Text, HTML

| | U | I | Document ID | Issue Date | Pages | Title | Current OR | Current XRef | Retrieval Cla | Inventor | S | C | P | 3 | Image 1* |
|----|---|---|----------------------|------------|-------|--|------------|-----------------------------|---------------|-----------------------|---|---|---|---|----------|
| 1 | | | US 20040056248 AI | 20040325 | 12 | Test key for detecting electrical isolation between a word line and a d | 257/48 | | | Liu, Chih-Cheng et al | R | | | | US 2004 |
| 2 | | | US 20030169629 AI | 20030911 | 49 | Semiconductor memory cell configuration and a method for produ | 365/200 | 257/E21.652 | | Goebel, Bernd et al | R | | | | US 2003 |
| 3 | R | | US 20020187648 AI | 20021212 | 85 | Material removal method for forming a structure. | 438/745 | 257/E21.011; 257/E21.166 | | Wu, Zhiqiang et al | | | | | US 2002 |
| 4 | R | | US 20020182872 AI | 20021205 | 85 | Material removal method for forming a structure. | 438/705 | 257/E21.011; 257/E21.166 | | Wu, Zhiqiang et al | | | | | US 2002 |
| 5 | R | | US 20020182816 AI | 20021205 | 83 | Material removal method for forming a structure. | 438/345 | 257/E21.011; 257/E21.166 | | Wu, Zhiqiang et al | | | | | US 2002 |
| 6 | R | | US 20020036310 AI | 20020328 | 16 | Trench capacitor having an insulation collar, and method of producing such | 257/301 | | | Lutzen, Jörn | | | | | US 2002 |
| 7 | R | | US 20020001960 AI | 20020103 | 89 | Material removal method for forming a structure. | 438/705 | 257/E21.011; 257/E21.166 | | Wu, Zhiqiang et al | | | | | US 2002 |
| 8 | R | | US 6756626 B2 AI | 20040629 | 15 | Trench capacitor having an insulation collar. | 257/301 | 257/302 | | Lutzen, Jörn | | | | | US 6756 |
| 9 | R | | US 6599840 B2 | 20030729 | 82 | Material removal method for forming a structure. | 438/705 | 257/E21.011; 257/E21.166 | | Wu, Zhiqiang et al | | | | | US 6599 |
| 10 | R | | US 6596648 B2 | 20030722 | 83 | Material removal method for forming a structure. | 438/745 | 257/E21.011; 257/E21.166 | | Wu, Zhiqiang et al | | | | | US 6596 |
| 11 | R | | US 6596642 B2 | 20030722 | 82 | Material removal method for forming a structure. | 438/705 | 257/E21.011; 216/38; | | Wu, Zhiqiang et al | | | | | US 6596 |
| 12 | | | US 6461967 B2 | 20021008 | 88 | Material removal method for forming a structure. | 438/705 | 216/38; 216/87; | | Wu, Zhiqiang et al | R | | | | US 6461 |
| 13 | | | US 6309975 B1 | 20011030 | 91 | Methods of making implanted structures. | 438/705 | 216/38; 216/87; | | Wu, Zhiqiang et al | R | | | | US 6309 |
| 14 | | | US 6261964 B1 | 20010717 | 91 | Material removal method for forming | 438/705 | 257/E21.011; | | Wu, Zhiqiang et al | | | | | US 6261 |

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| 15 | 33 | (trench\$2 adj capacitor\$1) and (connecting adj line\$1) | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2004/07/20 15:43 |
| 16 | 3730 | connecting adj region\$1 | USPAT; US-PGPUB; EPO; JPO; . DERWENT; IBM_TDB | 2004/07/20 15:44 |
| 17 | 26 | (trench\$2 adj capacitor\$1) and (connecting adj region\$1) | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2004/07/20 15:44 |